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How to cite:

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Version: Accepted Manuscript

Link(s) to article on publisher's website: http://dx.doi.org/doi:10.1016/j.tsf.2007.11.002

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The pH-dependent adhesion of nanoparticles to self-assembled monolayers on gold

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Received 19 March 2007; received in revised form 1 November 2007; accepted 1 November 2007

11 Abstract

The effect of pH on the adhesion of silica and polystyrene latex nanoparticles, presenting hydroxyl and carboxyl acid surface chemistries respectively, to self-assembled monolayers (SAMs) has been investigated. The SAMs studied were 1-dodecanethiol, 11-mercaptoundecanoic acid and an original pyridine-terminated SAM. Adhesion of nanoparticles to the SAMs was found to decrease with increasing pH due to increased repulsive forces between surfaces, as a result of the deprotonation of surface moieties on the nanoparticles. A range of surface morphologies for the adsorbed nanoparticles was observed for the systems studied.

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19 Keywords: Self-assembled monolayer; Nanoparticle; Adhesion; Surface chemistry; pK_a

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21 **1. Introduction**

The formation of nanostructures is a prime example of the 22'bottom-up' fabrication process and is currently a subject of 2324significant research activity, with number of techniques typically being employed in 'bottom-up' processes. The 25deposition of nanoparticles onto surfaces is an obvious example 26 of such research, with the ability to assemble nanoparticles into 27 patterns and arrays being one step on the road towards the 28construction of nanodevices and nanofunctional materials [1]. 29Mendes et al. [2] discussed the challenge of understanding how 30 ordered or complex structures can form spontaneously by self-31assembly, and the problems inherent with controlling such 32 processes. Similarly, Jonas et al. [1] discussed the possible 33 applications of these nanodevices and nanofunctional materials, 34

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which include anti-reflective materials [3,4], biosensors [5], and 35 superhydrophobic surfaces [6]. Other examples of 'bottom-up' 36 research include the production of nanopatterned surfaces [7,8], 37 perhaps employing nanolithographic techniques [9]. The 38 formation of deoxyribonucleic acid-mediated artificial nano- 39 biostructures has also been reported [10].

The selective arrangement of nanoparticles on patterned 41 surfaces displaying two or more surface chemistries has been 42 reported by a number of authors. For example, Krüger et al. [11] 43 reported the pH-selective adsorption of latex nanoparticles onto 44 photolithographically patterned silane self-assembled mono- 45 layers (SAMs), while Mendes et al. [12] reported the 46 preferential adsorption of citrate-passivated Au nanoparticles 47 onto NH₂-terminated regions of a chemically modified NO₂- 48 terminated silane SAM, which had been patterned using e-beam 49 lithography. Au and Ag nanoparticles have been used in this 50 research area [13] as they can be passivated with thiols and can 51 offer a variety of surface chemistries once passivated. For 52 example, thiol-passivated Au nanoparticles, which were first 53 reported by Brust et al. [14], have been employed in the 54

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Scheme A1. Synthetic route employed for the synthesis of SAM compound 3. Scheme uploaded electronically.

formation of thin films on silane SAMs, yielding structures with 55different films providing a range of colours and reflectivities 5657[15].

Nanoparticles are one example of colloidal materials, or 58 colloids. Colloids are found in many aspects of new and old 59 technologies. For example, colloidal clay, polymer latex and 60 calcite particles are used in paper manufacture, each conferring 61 a different function to the finished product. Colloids are found 62 in many other day-to-day items, such as the ink in ball point 63 pens, photocopiers, paints, cosmetics and bricks, and are also 64 an important aspect of biological, medicinal and agricultural 65 systems [16]. The selective deposition of colloids onto surfaces, 66 67 particularly patterned surfaces, is often controlled by electrostatic, hydrophobic or biospecific interactions [17]. Understand-68 ing the mechanisms behind such interactions and the variables 69 which will affect their adhesion is a key part of working towards 70 nanodevices and nanofunctional materials. The work presented 71here investigates the deposition of colloidal nanoparticles with 72different surface chemistries onto SAMs which also present a 73 range of surface chemistries. These studies are performed over the 74 pH range 1-11, as pH is often an important parameter in con-75 trolling the adhesion between surfaces [7]. 76

2. Experimental details 77

2.1. Chemical reagents 78

Three SAM compounds were employed for the deposition of 79 SAMs on Au. 11-mercaptoundecanoic acid (1, Sigma, UK) and 80 1-dodecanethiol (2, Sigma, UK) were used as received. An 81 original dialkyl disulfide (3) containing a terminal pyridine 82 moiety was synthesised as described in the appendix, the 83 synthetic route being shown in Scheme A1. The structures, 84 contact angle behaviour and the pK_{as} (in aqueous solution) of the 85 terminal moieties of the SAMs are listed in Table 1. For the 86 pyridine-terminated SAM a prediction of the terminal moiety pK_a 87 was made using the Hammett and Taft equations for heteroaro-88 matic acids and bases [18]. The assumed terminal pK_{as} for the 89 other SAMs were based on their shorter chain analogues, whose 90 91 pK_{as} are well established, because inductive effects fall off rapidly

with distance in saturated hydrocarbons [18]. Therefore, the 92 terminal methyl moiety of a 1-dodecanethiol SAM was assumed 93 to have a pK_a of 50 in aqueous solution, analogous to ethane 94 [19]. Likewise, the terminal carboxylic acid moiety of a 95 11-mercaptoundecanoic acid SAM was assumed to have a pK_a of 96 4.75 in aqueous solution, analogous to ethanoic acid [20,21]. 97

The organic solvent used for SAM formation was HPLC grade 98 ethanol (Fisher Scientific, UK). Piranha solution was used for 99 glassware cleaning and for cleaning Au slides prior to SAM 100 formation. Piranha solution was made as a 3:7 mixture of 30% 101 laboratory reagent grade hydrogen peroxide (Fisher Scientific, 102 UK) and analytical reagent grade concentrated sulfuric acid 103 (Fisher Scientific, UK). Piranha solution is a very strong oxidising 104 agent and has been known to detonate spontaneously upon contact 105 with organic material. Therefore, eye protection (Fisher Scientific, 106 UK) and nitrile gloves (Bodyguards, UK) were worn at all times, 107 and as a precaution H₂O ice was used as a quenching agent. 108

Table 1

t1.1Chemical structures of SAM compounds 1-3, their H₂O contact angle behaviour and terminal moiety pK_as in aqueous solution t1.2



When required for pH adjustments, NaOH solutions were 109 made by dissolving NaOH pellets (Fisher Scientific, UK) in 110 Ultra-High Ouality (UHO) H₂O at room temperature, followed 111 112by dilution as required. HCl solutions were made by diluting 11.65 M HCl solution (Fisher Scientific, UK) with UHO H₂O at 113 room temperature. All pH measurements were performed using 114 an IQ150 pH meter (IO Scientific Instruments) operating at 115 room temperature. 116

117 2.2. Deposition of Au thin films and formation of SAMs

Au was deposited onto clean glass microscope slides (BDH, 118 UK) by thermal evaporation using an Auto 306 vacuum 119 evaporation chamber (Edwards, UK). Cr was used as an 120adhesion promoter, as priming the glass surface with Cr or Ti 121 improves adhesion of Au, which has been reported by various 122authors when describing their preparation of Au films [8,22-123 30]. The chamber pressure was reduced to $\sim 10^{-5}$ Pa using a 124two-stage pumping system. Cr pieces of 99.99% purity (Agar 125Scientific, UK) were heated by electrical resistance using a 126voltage of 30 V and a current of 3 A until ~ 5 nm of Cr had been 127 deposited onto the glass surface. Au wire of 99.99+% purity 128 (Advent Research Materials, UK) of 0.5 mm diameter was 129placed into a Mo boat (Agar Scientific, UK) and was heated by 130 electrical resistance using a voltage of 10 V and a current of 3 A 131 until ~ 100 nm of Au had been deposited onto the desired surface. 132Deposition was monitored using an in situ quartz crystal 133 microbalance thickness monitor. The deposition rate for both Cr 134and Au was in the range 0.05-0.10 nm s⁻¹. Nitrile gloves 135 136 (Bodyguards, UK) were worn during all handling procedures and Dumostar tweezers (Agar Scientific, UK) were employed to 137minimise contact with the samples whenever it was practical to do 138 so. Where Au substrates were required to be cut up into smaller 139pieces, a diamond-tipped scriber (Agar Scientific, UK) was used. 140 Any dust produced was blown away with Ar gas. 141

All glassware used in SAM formation was cleaned prior to use 142by immersion in piranha solution at room temperature for ~ 1 h. 143Cleaning with piranha solution was followed by rinsing with 144 copious amounts of 18 M Ω deionised H₂O (Elga UHQ-PS) and 145drying in an oven at 140 °C. SAMs were prepared by immersing 146 Cr-primed, Au-coated glass microscope slides in 1 mM solutions 147 of the SAM compounds for 24 h (11-mercaptoundecanoic acid 148 and 1-dodecanethiol) and 48 h (pyridine SAM compound), using 149ethanol as a solvent. All Au substrates were cleaned prior to SAM 150151 formation by immersion in piranha solution at room temperature for 10 min. Cleaning with piranha solution was followed by 152rinsing with copious amounts of 18 M Ω deionised H₂O (Elga 153UHQ-PS) and rinsing with copious amounts of ethanol. After the 154desired immersion time, Au substrates were removed from the 155SAM solution and rinsed with copious amounts of ethanol, before 156being blown dry using Ar gas. 157

158 2.3. SAM characterisation procedures

Characterisation of SAMs formed on Au substrates involved
 assessing their wetting behaviour, elemental composition and
 thickness, employing dynamic water contact angle measure-

ments, X-ray photoelectron spectroscopy (XPS) and ellipso- 162 metry, respectively. Figs. A1–A3 show the XPS spectra 163 obtained for SAMs 1–3 respectively, while Table A1 lists the 164 SAM thicknesses measured using ellipsometry. 165

Dynamic H₂O contact angles were measured using a home- 166 made stage apparatus, employing a Charge-Coupled Device 167 (CCD) KP-M1E/K camera (Hitachi) and FTA Video Analysis 168 software v1.96 (First Ten Angstroms) for analysis of the contact 169 angle of a droplet of UHQ H₂O at the three-phase intersection 170 point. All data was collected at room temperature and pressure 171 under ambient humidity conditions. A 25 µL gastight syringe 172 (Hamilton) was used for changing the volume of the droplet for 173 all measurements, allowing volume adjustments of $\sim 1 \,\mu\text{L}$ to be 174 performed manually, if necessary. The droplet was released onto 175 the sample surface from a blunt-ended needle of $\sim 1 \text{ mm }_{176}$ diameter (Hamilton). Frames for the video analysis were 177 captured at a rate of 0.12 Hz, usually yielding a minimum of 178 ten frames for both the advancing contact angle and the receding 179 contact angle. Mathematical analysis of the contact angle was 180 performed assuming a non-spherical droplet shape, with manual 181 designation of the baseline for each surface analysed. Data for 182 the advancing contact angle were only chosen when the droplet 183 width was increasing. Similarly, data for the receding contact 184 angle were only chosen when the droplet width was decreasing. 185 The calculated contact angles for each frame during the 186 advancing or receding droplet movement were averaged to 187 give mean values for both the advancing and receding contact 188 angle behaviour of the surface. A minimum of 7 measurements 189 were performed for each sample. 190

Ellipsometry measurements were performed using a spectro- 191 scopic ellipsometer (Jobin-Yvon/Horiba) operating with Del- 192 taPsi2 v2.0.8 software. Ellipsometer calibration and alignment 193 of the Polariser and Detector were performed using an Al 194 reference sample, which has a thermally grown Al_2O_3 layer. The 195 angle of incidence between the analyser and the polariser was set 196 to 70° and was maintained for all subsequent measurements. The 197 light wavelength range used for all measurements was 280– 198 800 nm. All measurements were made under conditions of 199 ambient temperature, pressure and humidity. SAM thicknesses 200 are averages of a minimum of six measurements, each made at a 201 different location on the substrate. Precautions were made to 202



Fig. 1. XPS results for SiO_2 nanoparticles deposited onto SAMs 1–3: Au:Si peak area ratio.

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Please cite this article as: J. Bowen, et al., Thin Solid Films (2007), doi:10.1016/j.tsf.2007.11.002



Fig. 2. XPS results for COOH–PL nanoparticles deposited onto SAMs 1–3: Au: C peak area ratio.

avoid performing measurements on visibly defective locations 203 on the sample. Mathematical modelling of the SAM thickness 204was performed for each measurement. The SAM thickness 205calculations were based on a three-phase ambient/SAM/Au 206model, in which the SAM was assumed to be isotropic and 207assigned an initial refractive index of 1.50 [31-33]. The 208 refractive index of a SAM has also been reported as 1.45 209 [34,35]. However, it was found that whether the starting value for 210 the iterative calculation process was 1.45 or 1.50, the outcome of 211 the modelling process did not vary. The SAM was modelled 212

using a Cauchy transparent layer, whose initial thickness was 213 varied using a multiguess iterative calculation procedure. The 214 single outcome of each iteration process was the result with the 215 lowest χ^2 . A minimum of five different initial values for the 216 SAM thicknesses were chosen for each SAM measurement. 217 Those results with the lowest χ^2 for each measurement made 218 were averaged to give a mean SAM thickness. 219

XPS analysis of SAMs was performed using an Escalab 250 220 system (Thermo VG Scientific) operating with Avantage v1.85 221 software. An Al K α X-ray source was used, providing a 222 monochromatic X-ray beam with incident energy of 1486.68 eV. 223 All measurements were made at a pressure of ~ 5×10^{-9} mbar. A 224 circular spot size of ~ 0.2 mm² was employed throughout all 225 measurements. Samples were immobilised onto stainless steel 226 sample holders, using both double-sided carbon sticky tape 227 (Shintron tape, Shinto Paint Company) and stainless steel or 228 copper sample clips (Thermo VG Scientific). The use of clips 229 provided conductivity between the sample surface and the 230 sample holder, because although the Au film is conductive, the 231 glass substrate is insulating. By providing a conductive link 232 between the sample surface and the sample holder, surface 233 charge retention during measurement was minimised. 234

Low resolution survey spectra were obtained using a pass 235 energy of 150 eV over a binding energy range of -10 eV to 236 1200 eV, obtained using 1 eV increments. Recorded low 237 resolution spectra would typically be an average of 5 scans. All 238



Fig. 3. 50 µm × 50 µm AFM images for SiO₂ nanoparticles deposited onto SAM 1 at pH 1-9 (height scale is 100 nm).

high resolution spectra were obtained using a pass energy of
20 eV over a binding energy range of 20–30 eV, centred around
a chosen photoelectron binding energy, obtained using 0.1 eV
increments. A dwell time of 20 ms was employed when
collecting data from each binding energy increment for all
measurements. Recorded high resolution spectra would typically be an average of at least 10 scans.

246 2.4. Nanoparticle deposition and sample analysis procedures

Two types of nanoparticles were deposited onto SAMs. The nanoparticles were used as received (0.5 g in 10 mL suspension) and were SiO_2 (160 nm diameter, Bangs Labs, USA) and COOH-terminated polystyrene latex (PL) (40 nm diameter, 250 Bangs Labs, USA). Deposition was performed over the pH 251 range 1–11 for the polystyrene latex nanoparticles, but over the 252 pH range 1–9 for the SiO₂ nanoparticles, because SiO₂ 253 dissolves at pH>10 [36]. In each case, 0.1 mL of nanoparticle 254 suspension was added to 20 mL of aqueous solution at the 255 desired pH. Each SAM was immersed in the nanoparticle 256 solution for 2 h before being removed, whereupon it was rinsed 257 with aqueous solution of the same pH as the immersion 258 solution, followed by drying under a stream of Ar gas. 259

Samples were analysed using atomic force microscopy 260 (AFM) using a Dimension 3100 Nanoscope AFM (Veeco, UK) 261 operating in tapping mode under ambient conditions. The AFM 262



Fig. 4. 50 µm×50 µm AFM images for COOH-PL nanoparticles deposited onto SAM 1 at pH 1-11 (height scale is 100 nm).

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was housed on a vibration isolation table to minimise the effect 263 of ambient noise on imaging quality. Nanoscope v5.12 software 264265(Veeco, UK) was used throughout for both real-time analysis and post-capture image processing. Tapping Mode AFM 266 imaging was performed using rectangular 180 µm length 267pyramidal-tipped Si cantilevers (Veeco, UK) with nominal 268spring constants of 40 N m⁻¹ and resonant frequencies in the 269range 250-350 kHz. All images were acquired at scan rates 270between 0.2-2.0 Hz, each image being composed of 271512×512 pixels. Samples were immobilised onto steel SPM 272specimen disks (Agar Scientific, UK) using double-sided sticky 273tape (3M, UK) prior to AFM analysis. All sample handling was 274 carried out using Dumostar tweezers (Agar Scientific, UK) to 275minimise the risk of sample contamination. 276

277 Samples were analysed by XPS as described in Section 2.3. The area of the Au 4f photoelectron peaks from the Au surface was 278calculated from the spectra recorded from all samples. For those 279samples with SiO₂ nanoparticles adhered on them, the area of the 280Si 2p photoelectron peaks was calculated. Similarly, for those 281 samples with COOH-PL nanoparticles adhered on them, the area 282 of the C 1 s photoelectron peaks was calculated. The contribution 283 to the C 1 s photoelectron peaks from the underlying SAM was 284 assumed to be negligible in comparison to the contribution from 285 the COOH-PL nanoparticles. The Au:Si or Au:C ratios for each 286 SAM/nanoparticle/pH combination were then calculated using 287relative sensitivity factors according to Wagner et al. [37]. 288

3. Results and discussion

The adhesion of SiO₂ nanoparticles and COOH-PL 290 nanoparticles to SAMs 1-3 is presented in the following 291 sections. The Au:Si ratios for the SAM/SiO₂ nanoparticle 292 systems, and the Au:C ratios for the SAM/COOH-PL 293 nanoparticle systems, as determined by XPS, are presented in 294 Figs. 1 and 2 respectively. 295

3.1. SAM 1 (carboxylic acid-terminated)

SAM 1 presents a terminal carboxylic acid moiety with an 297 assumed pK_a of 4.75 in aqueous solution. Therefore the pH of 298 the aqueous electrolyte from which the nanoparticles are 299 deposited will determine the protonation state of the SAM 300 and may affect the observed patterns of adhesion. Figs. 3 and 4 301 show the AFM images SiO₂, COOH-PL and R₃N-PL 302 nanoparticle adhesion to SAM 1 as a function of pH. 303

Fig. 3 reveals that there is significant adhesion of SiO₂ 304 nanoparticles to SAM 1 at pH 1 and pH 3, while at pH 5 and pH 305 9 there is little adhesion of SiO₂ nanoparticles. Such behaviour 306 suggests that as the pH increases from 3 to 5 the dissociation of 307 the SiOH groups on the SiO2 nanoparticles introduces a 308 sufficiently repulsive interaction to prevent adhesion of SiO₂ 309 nanoparticles to the SAM through hydrogen bonding. Similarly, 310 at pH 5 the terminal COOH groups of the SAM may have 311



Fig. 5. 50 µm × 50 µm AFM images for SiO₂ nanoparticles deposited onto SAM 2 at pH 1-9 (height scale is 100 nm).

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dissociated to the carboxylate anion, which would further 312 increase the repulsive interaction between the SiO₂ nanoparti-313 cles and the SAM. However, the dissociation of the COOH 314 moiety in SAMs has been investigated by Smith et al. [38,39] 315and has been reported to increase from 4.75 towards 8.0. The 316 SiO₂ nanoparticle surface consists of hydrophilic SiOH (silanol) 317groups [40], at a density of 4-5 SiOH groups nm^{-2} [36]. SiO₂ 318 has a negative zeta potential in aqueous solution at pH>3.5, due 319to the dissociation of SiOH groups to SiO⁻, and the zeta 320 potential will become increasingly negative as pH increases, 321causing the electrostatic repulsion between nanoparticles to 322 increase. Nevertheless, for the system investigated here it is 323 anticipated that a repulsive interaction will exist between the 324

SAM and the SiO₂ nanoparticles whether the SAM surface 325 consisted of either dissociated or undissociated COOH 326 moieties. The Au:Si ratios obtained from XPS analysis, as 327 shown in Fig. 1, do not agree entirely with the results of the 328 AFM analyses, but it is believed that the morphology of the 329 nanoparticles is a contributory factor in this situation. The 330 aggregation of SiO₂ nanoparticles on the SAM, at pH 1 in 331 particular, may give rise to a higher Au:Si ratio than might be 332 expected, as Si 2p photoelectrons leaving the surface will have 333 to pass through a substantially greater amount of surface 334 material than the Au 4f photoelectrons leaving the surface. 335 Hence, the Au:Si ratio appears to be higher than it actually is. A 336 similar situation may also have occurred at pH 3, at which pH 337



Fig. 6. 50 µm×50 µm AFM images for COOH-PL nanoparticles deposited onto SAM 2 at pH 1-11 (height scale is 100 nm).

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aggregation was also observed, although the nanoparticle
aggregates appeared more loosely bound together, which lead
to the streaking visible in the AFM image for these pHs.

Figs. 2 and 4 reveal that COOH–PL nanoparticles exhibit little adhesion to SAM 1 at all pHs. However, it would appear from Fig. 2 that there are slightly more COOH–PL nanoparticles adhered to the SAM at pHs 5 and 9 than at the other pHs, which suggests that adhesion was greatest at those pHs around the pK_a of the COOH moiety.

347 3.2. SAM 2 (methyl-terminated)

SAM 2 presents a terminal methyl moiety with an assumed p K_a of 50 in aqueous solution. Therefore the pH of the aqueous electrolyte from which the nanoparticles are deposited will not affect the protonation state of the SAM, and will not affect the adhesion. Figs. 5 and 6 show the AFM images for SiO₂ and COOH–PL nanoparticle adhesion to SAM 2 as a function of pH.

Figs. 1 and 5 reveal that adhesion of SiO_2 nanoparticles to the methyl-terminated SAM surface occurs at pH 1–9 and decreases somewhat with increasing pH. There is no electrostatic repulsion between the SAM and the SiO_2 nanoparticles, due to the nature of the methyl moiety, hence the adhesion of SiO_2 nanoparticles to the SAM will be dominated by van der Waals forces.

Figs. 2 and 6 reveals that the adhesion of COOH–PL nanoparticles to SAM 2 varies little with pH, although the AFM images indicate differences in the morphology of the deposited COOH– 362 PL nanoparticles, particularly at pH 3. It may be that at pH 3 there 363 exists insufficient electrostatic repulsion between the COOH–PL 364 nanoparticles to prevent aggregation and deposition onto the 365 SAM. At all other pHs, adhesion of COOH–PL nanoparticles to 366 the SAM will be dominated by van der Waals forces. 367

368

3.3. SAM 3 (pyridine-terminated)

SAM 3 presents a terminal pyridine moiety with a predicted $_{369}$ p K_a of 5.60 in aqueous solution. Therefore the pH of the $_{370}$ aqueous electrolyte from which the nanoparticles are deposited $_{371}$ will determine the protonation state of the SAM. Figs. 7 and 8 $_{372}$ show the AFM images for SiO₂ and COOH–PL nanoparticle $_{373}$ adhesion to SAM 3 as a function of pH. $_{374}$

Fig. 1 reveals that as pH increases the Au:Si ratio remains $_{375}$ approximately constant, which suggests that the adhesion of $_{376}$ SiO₂ nanoparticles to SAM 3 remained approximately constant $_{377}$ with pH. This is in contrast to the AFM results, presented in $_{378}$ Fig. 7, which reveal that as pH increases the number of SiO₂ $_{379}$ nanoparticles deposited decreases. It is believed that the $_{380}$ morphology of the nanoparticles is a contributory factor in $_{381}$ this situation, as discussed for SAM 1. Briefly, the aggregation $_{382}$ of SiO₂ nanoparticles on the SAM increases the amount of $_{383}$ surface material which the photoelectrons leaving the surface $_{384}$ must pass through before being detected, which can serve to $_{385}$



Fig. 7. 50 µm×50 µm AFM images for SiO₂ nanoparticles deposited onto SAM 3 at pH 1-9 (height scale is 100 nm).

distort the measured photoelectron counts. At pH 1 and pH 3 it 386 would be expected that the SiO₂ nanoparticles have a little or no 387 surface charge, and therefore the observed aggregation of the 388 SiO₂ nanoparticles, leading to the deposition of aggregates on 389 the SAM, might also be expected. At pH 5 and pH 9 the SiO₂ 390 nanoparticles will exhibit negatively charged surfaces and 391therefore will repel each other, preventing aggregation. The 392 terminal pyridinium moieties of SAM 3 will become increas-393ingly dissociated with increasing pH, which will serve to 394 decrease the cationic surface charge of the SAM. This 395decreasing surface charge will also promote the adhesion of 396 fewer SiO₂ nanoparticles to the SAM. 397

Fewer SiO₂ nanoparticles are adsorbed onto SAM 1 than to SAMs 2 and 3, particularly at pH>5, due to the deprotonation of both the SiO₂ nanoparticle surface and the 400 SAM terminal moieties, leading to electrostatic repulsion 401 between the SAM and the SiO₂ nanoparticles, preventing 402 adhesion. For SAM 2 there will be no deprotonation of its 403 terminal moieties with increasing pH. For SAM 3, the 404 deprotonation of the terminal pyridine moiety will still leave 405 a surface capable of some electrostatic attraction with the 406 SiO₂ nanoparticles. Therefore, only SAM 1 does not present 407 a surface capable of adhering SiO₂ nanoparticles at increased 408 pH.

Fig. 2 reveals that the Au:C ratio increases with increasing 410 pH, suggesting a decrease in adhesion of COOH–PL nano- 411 particles to SAM 3 between these pHs. This trend is in 412 approximate agreement with the AFM results, presented in 413



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Fig. 8. The decreasing adhesion of COOH-PL nanoparticles to 414 SAM 3 with increasing pH may be linked to the increasing 415dissociation of the surface COOH groups on the COOH-PL 416 nanoparticles with increasing pH. Adhesion of COOH-PL 417 nanoparticles to the SAM is reduced at pHs above the pK_a of the 418 COOH moiety, although the apparent pK_a of the moiety, which 419 is 4.75 in free solution, has been shown to increase when 420 present at a surface [38,39], for example when it is the surface 421 moiety of a SAM. For both the XPS and the AFM data, the 422 decrease in adhesion of COOH-PL nanoparticles to the SAM 423 occurs at pH greater than the pK_a of the COOH moiety. 424

425 4. Conclusions

The effect of electrolyte pH on the deposition and adhesion 426 of nanoparticles to SAMs presenting carboxylic acid, methyl 427and pyridine surface moieties has been investigated using AFM 428and XPS. Adhesion was found to vary with pH for many 429combinations of SAM and nanoparticle, with a number of 430different surface morphologies of nanoparticles being observed. 431The adhesion behaviour is believed to be linked to the 432 protonation state of the surface moieties on the nanoparticles, 433 rather than simply the contact angle behaviour of the SAM, 434whereby increasing pH often led to decreased nanoparticle 435 adhesion, probably due to increased repulsive interactions 436 between the SAMs and the nanoparticle, and also between 437 nanoparticles. Differences in nanoparticle adhesion were 438 observed between SAMs for the same nanoparticle and pH, 439 due to the different surface properties of each SAM, such as 440 441 pK_a . Further investigation on systems such as these could include the study of nanoparticle adhesion to hydroxyl-442 terminated SAMs and assessment of the mass of adhered 443 nanoparticles using a quartz crystal microbalance. 444

445 Acknowledgements

We acknowledge The University of Birmingham and
ACORN (A Collaboration on Research into Nanoparticles)
for financial support. We also acknowledge the assistance and
advice given by Professor G.J. Leggett and Dr. S. Sun at the
University of Sheffield, School of Chemistry.

451 Appendix A

The following supporting information is presented.
(i) Synthesis and characterisation data for SAM compound
(ii) Characterisation results for SAMs 1–3, consisting of
elemental composition as determined by X-ray photoelectron spectroscopy and thickness data as determined by
ellipsometry.

458 A.1. Synthesis and characterisation data for SAM compound 3

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- 460 A.1.1. Compound 5
- To a solution of 11-mercaptoundecanoic acid 4 (7.0 g, 32.1 mM) in C_2H_5OH (100 mL) heated under reflux was added

a solution of iodine (4.07 g, 16.03 mM) in C₂H₅OH (50 mL). 463 Heating was continued for 12 h after which the reaction was 464 allowed to cool to room temperature and washed with a 465 saturated aqueous solution of Na₂S₂O₃ (50 mL). The products 466 were extracted into CH_2Cl_2 (3 × 50 mL) and dried (MgSO₄), 467 filtered and the solvent was removed in vacuo. The residues 468 were purified by recrystallisation from CH₂Cl₂/hexane. The 469 feathery white crystals were filtered from the mother liquor, 470 washed with ice-cold hexane and dried in vacuo affording 5 471 (6.47 g, 82%). m/z (ES) 513 $[M+Na]^+ \delta_H$ (500 MHz, 472 $(CD_3)_2SO$ 4.09 (4H, q, J=7.3, 14.3 Hz), 2.65 (4H, t, 473 J=7.3 Hz), 2.26 (4H, t, J=7.3 Hz), 1.61 (8H, m), 1.34 (30H, 474 m). δ_C (400 MHz, CDCl₃) 173.9, 60.1, 39.1, 34.4, 29.3, 29.2, 475 28.5, 24.9, 14.2. Elemental analysis of C₂₆H₅₀O₄S₂ requires C 476 63.67%, H 10.20%. Elemental analysis found C 63.52%, H 477 10.48%. 478

A.1.2. Compound 6

To a vigorously stirred solution of 5 (4.75 g, 9.68 mM) in 480 tetrahydrofuran (THF) (100 mL) was added a solution of 481 potassium hydroxide (1.63 g, 29.0 mM) in H₂O/C₂H₅OH (1:1, 482 20 mL). The reaction was stirred for 12 h, and acidified with 483 HCl (aq, 2 M, 20 mL) upon which a white solid precipitated. 484 The solid was filtered off, washed with H₂O (100 mL), cold 485 C₂H₅OH (100 mL) and dried *in vacuo* affording 6 as white 486 plate-like crystals (4.20 g, 99%). *m/z* (ES) 457 [M+Na] ⁺. $\delta_{\rm H}$ 487 (400 MHz (CD₃)₂SO) 3.5 (2H, s), 2.68 (4H, *t*, *J*=8.0 Hz), 2.14 488 (4H, *t*, *J*=8.0 Hz), 1.62 (4H, m), 1.46 (4H, m), 1.2 (24H,m). $\delta_{\rm C}$ 489 (400 MHz, (CD₃)₂SO) 174.5, 38.0, 33.7, 28.9, 28.8, 28.6, 28.6, 490 27.8, 24.5. Elemental analysis of C₂₂H₄O4S₂ requires C 491 60.82%, H 9.67%. Elemental analysis found C 60.78%, H 492 9.70%.

A.1.3. Compound 3

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To a solution of 6 (0.100 g, 0.23 mM) in dry THF (10 mL) 495 cooled to 0 °C under an N₂ atmosphere was added 1-(3-496 dimethylaminopropyl)-3-ethyl-carbodiimide hydrochloride 497 (0.272 g, 1.38 mM) and a catalytic amount of 4-dimethyl- 498 aminopyridine. The mixture was stirred for 30 min and 3-499 pyridinepropanol (0.094 g, 0.69 mM) was added over 10 min, 500 followed by further stirring for 24 h under an N₂ atmosphere 501 at room temperature. The white precipitate was filtered and 502 the filtrate was diluted with CH₂Cl₂ (30 mL) and washed 503 with H_2O (3×30 mL), followed by 10% aqueous NaHCO₃ 504 (10 mL) and saturated (aqueous) NaCl (5 mL). The organic 505 phase was dried (MgSO₄), filtered and the filtrate evaporated 506 to dryness under reduced pressure. The residue was purified 507 by silica gel column chromatography (eluent: CH2Cl2/EtOAc, 508 3:1) to yield 3 (0.045 g, 29%) as a white solid. m/z (ES) 695 509 $[M+Na]^+$. δ_H (400 MHz, CDCl₃) 8.4 (4H, m), 7.47 (2H, m), 510 7.19 (2H, m), 4.07 (4H, t, J=6.4 Hz), 2.66 (8H, m), 2.27 511 (4H, t, J=8.0 Hz), 1.94 (4H, m), 1.66 (8H, m), 1.32 (24H, 512 m). δ_{C} (400 MHz, CDCl₃) 173.7, 149.9, 147.5, 136.3, 135.6, 513 123.2, 63.1, 39.0, 34.2, 29.8, 29.3, 29.1, 28.4, 24.9. 514 Elemental analysis of C₃₈H₆₀O₄N₂S₂ requires C 67.75%, 515 H 8.91%, N 4.16%. Elemental analysis found C 67.80%, 516 H 8.82%, N 4.07%. 517

Please cite this article as: J. Bowen, et al., Thin Solid Films (2007), doi:10.1016/j.tsf.2007.11.002

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A.2. Characterisation results for SAMs 1-3



Fig. A2. XPS spectra for SAM 2. Figure uploaded electronically.



Fig. A3. XPS spectra for SAM 3. Figure uploaded electronically.

Table A1 Ellipsometrically measured thicknesses for SAMs 1–3		
SAM	Calculated thickness range (nm)	Measured thickness (nm)
1	1.32–1.53	1.09 ± 0.16
2	1.34–1.55	1.45 ± 0.15
3	1.94–2.24	1.42 ± 0.31

A thickness range for each SAM was calculated by 533 estimating the length of the molecular structures of compounds 5341-3 using ChemDraw Ultra (v7.0.1, CambridgeSoft, UK) and 535Chem3D Ultra (v7.0.0, CambridgeSoft, UK) software. The 536 upper limit of the range is the full length of the SAM molecule. 537The chosen lower limit of the range is the height of the SAM 538 molecule at a tilt angle of 30° to the surface normal. 539

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